



EE141-Spring 2010 Digital Integrated Circuits

Lecture 16
Ratioed Logic
Dynamic Logic

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Administrativa

- ❑ Project Phase 1 Done – Thanks for the timely response.
- ❑ Phase 2 to be announced We – Launched on Fr.
- ❑ Hw 6 due on Fr.

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Class Material

- Last lecture
 - Pass transistor logic
 - CMOS Layout
- Today's lecture
 - Ratioed Logic
 - Dynamic Logic
- Reading (Ch 6)

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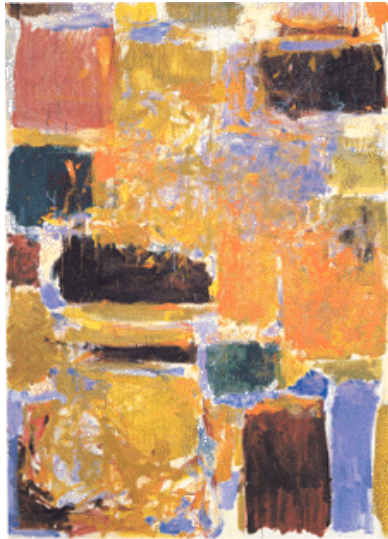
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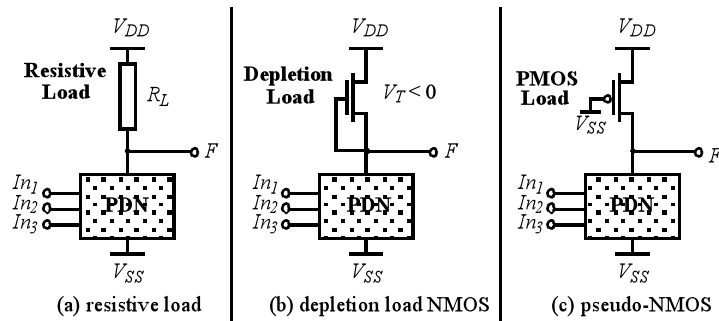
Ratioed Logic

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Ratioed Logic



Goal: build gates faster/smaller than static complementary CMOS

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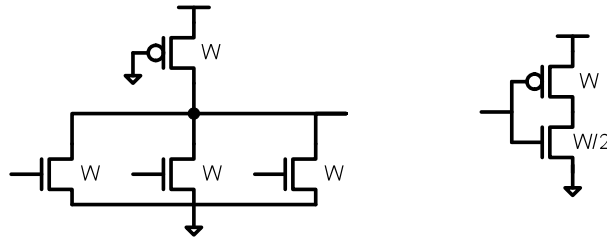
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Ratioed Logic LE

□ Rising and falling delays aren't the same

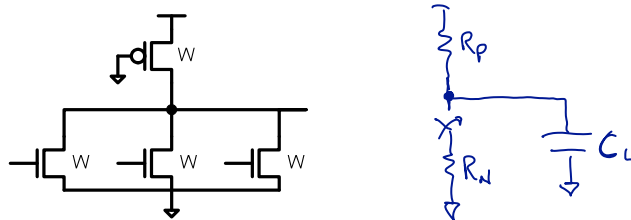
- Calculate LE for the two edges separately



□ For t_{pLH} :

- $C_{gate} = WC_G$ $C_{inv} = (3/2)WC_G$ $LE_{LH} =$

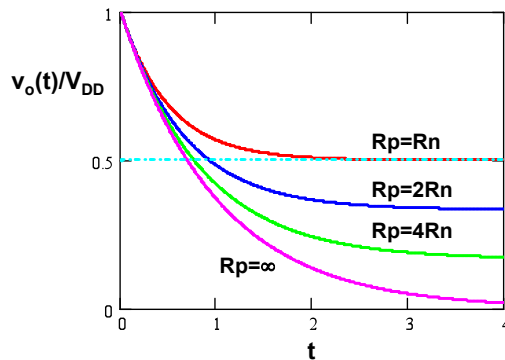
Ratioed Logic LE (pull-down edge)



□ What is LE for t_{pHL} ?

- Switch model would predict $R_{eff} = R_n || R_p$
 - Would that give the right answer for LE?

Response on Falling Edge



$$\tau = \frac{R_n \cdot R_p}{R_n + R_p} \cdot C$$

$$\frac{v_o(t)}{V_{DD}} = \frac{R_n}{R_n + R_p} + \left(1 - \frac{R_n}{R_n + R_p}\right) e^{-t/\tau}$$

- Time constant is smaller, but it takes more time to complete 50% V_{DD} transient (*arguably*)
 - R_p actually takes some current away from discharging C

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Ratioed Logic Pull-down Delay

- Think in terms of the current driving C_{load}
- When you have a conflict between currents
 - Available current is the difference between the two
 - In pseudo-nMOS case:

$$R_{drive} = \frac{1}{1/R_n - 1/R_p} \longrightarrow R_{drive} = \frac{R_n}{1 - (R_n/R_p)}$$

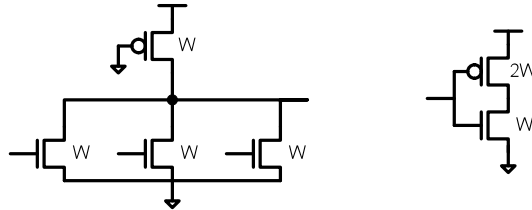
- (Works because $R_p \gg R_n$ for good noise margin)

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Ratioed Logic LE (pull-down edge)



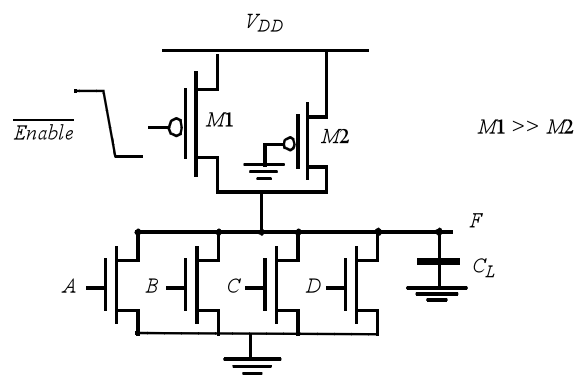
□ For t_{pHL} (assuming $R_{sqp} = 2R_{sqn}$):

- $R_{gate} = R_n / (1 - R_n/R_p) = 2R_n$ $R_{inv} = R_n$
- $C_{gate} = WC_G$ $C_{inv} = 3WC_G$
- $LE_{HL} =$

□ LE is lower than an inverter!

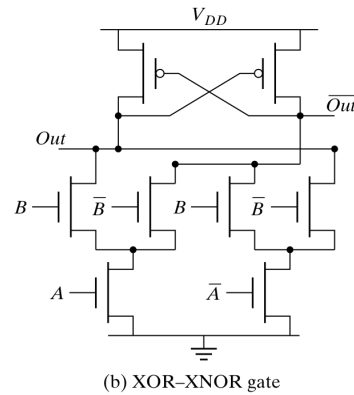
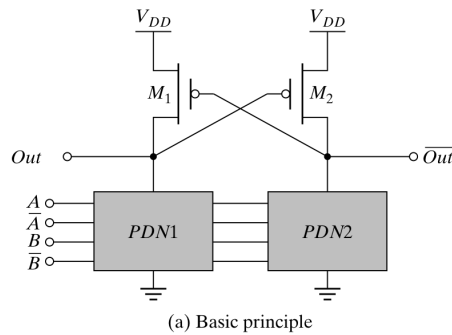
- But have static power dissipation...

Improved Loads



Adaptive Load

Improved Loads (2)



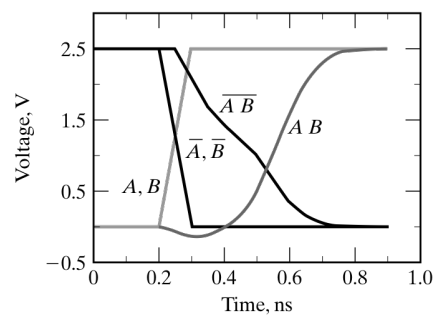
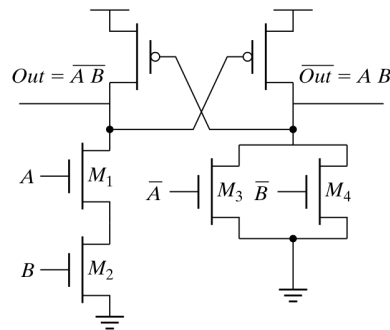
Differential Cascode Voltage Switch Logic (DCVSL)

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DCVSL Transient Response



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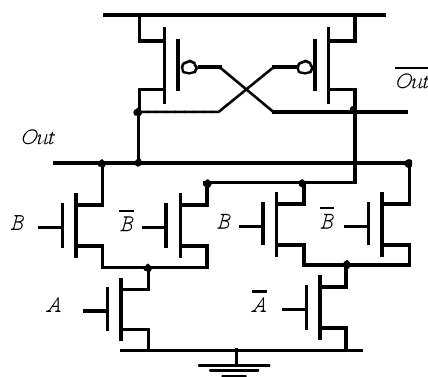
DCVSL Example1: AND

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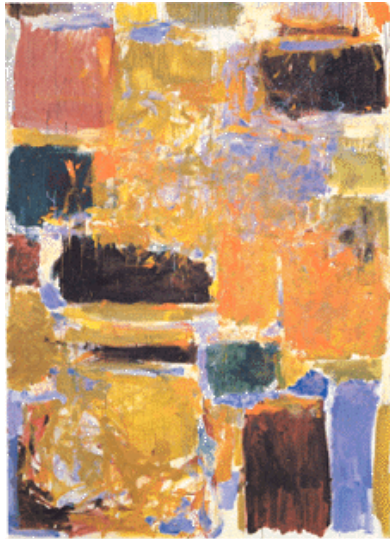
DCVSL Example2

**XOR/XNOR gate**

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Dynamic Logic

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Dynamic CMOS

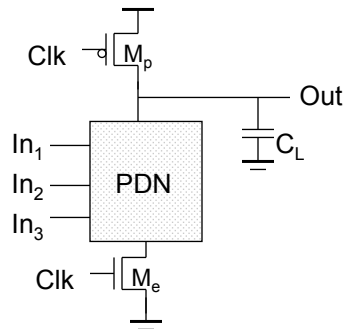
- ❑ In **static** circuits, at every point in time (except when switching) the output is connected to either GND or V_{DD} via a low resistance path.
 - fan-in of n requires $2n$ (n N-type + n P-type) devices
- ❑ **Dynamic** circuits rely on the temporary storage of signal values on the capacitance of high impedance nodes.
 - only requires $n + 2$ ($n+1$ N-type + 1 P-type) transistors

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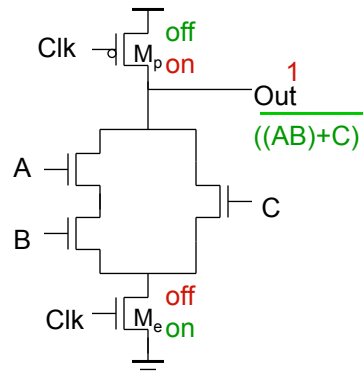
Dynamic Gate



Two phase operation

Precharge (Clk = 0)

Evaluate (Clk = 1)



Conditions on Output

- ❑ Once the output of a dynamic gate is discharged, it cannot be charged again until the next precharge operation.
- ❑ Inputs to the gate can make **at most** one transition during evaluation.
- ❑ Output can be in the high impedance state during and after evaluation (PDN off), state is stored on C_L

Properties of Dynamic Gates

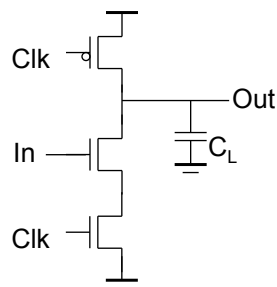
- Logic function is implemented by the PDN only
 - number of transistors is $N + 2$ (versus $2N$ for static complementary CMOS)
- Full swing outputs ($V_{OL} = \text{GND}$ and $V_{OH} = V_{DD}$)
- Non-ratioed - sizing of the devices does not affect the logic levels
- Faster switching speeds
 - reduced capacitance due to **lower input** capacitance (C_{in})
 - no I_{sc} , so all the current provided by PDN goes into discharging C_L

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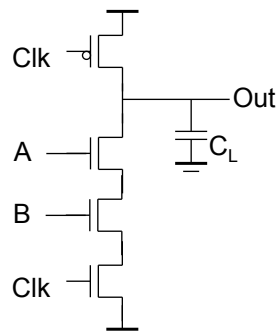
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LE of Dynamic Gates



$$C_{\text{gate}} =$$

$$LE =$$



$$C_{\text{gate}} =$$

$$LE =$$

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Properties of Dynamic Gates

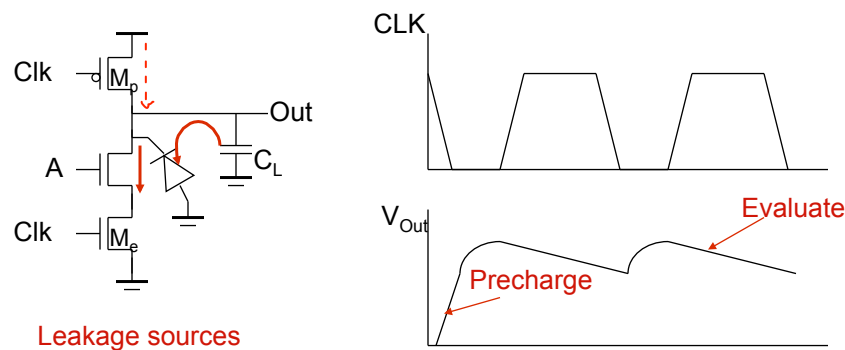
- ❑ Overall power dissipation usually **higher** than static CMOS
 - no static current path ever exists between V_{DD} and GND (including P_{sc})
 - no glitching
 - **higher transition probabilities**
 - **extra load on Clk**
- ❑ PDN starts to work as soon as the input signals exceed V_{Tn} , so V_M , V_{IH} and V_{IL} equal to V_{Tn}
 - low noise margin (NM_L)
- ❑ Needs a precharge/evaluate clock

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Issues in Dynamic Design 1: Charge Leakage



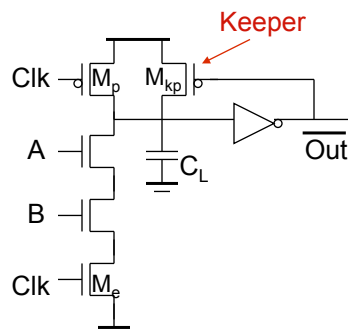
Dominant component is subthreshold current

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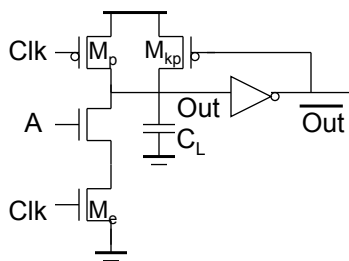
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Solution to Charge Leakage



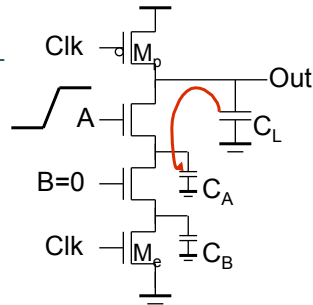
Same approach as level restorer for pass-transistor logic

Dynamic Gate VTC



Issues in Dynamic Design 2: Charge Sharing

- Charge initially stored on C_L
 - C_A previously discharged



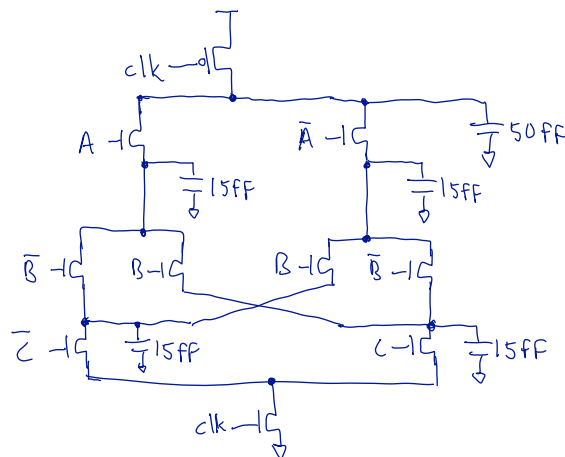
- When A rises, this charge is redistributed (shared) between C_L and C_A
- Makes Out drop below V_{DD}

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Charge Sharing Example

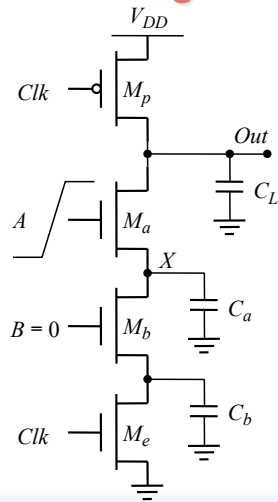


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Charge Sharing



- Two cases:
 - M_a stays on – complete charge share
 - M_a turns off – incomplete charge share

- Complete charge share:

- $Q_{Ca} = V_{Out} C_a$
 - $\Delta Q_{CL} = -V_{Out} C_a$

$$\rightarrow \Delta V_{Out} = -V_{DD} C_a / (C_a + C_L)$$

- Incomplete charge share:

- $Q_{Ca} = (V_{DD} - V_{TN}^*) C_a$
 - $\Delta Q_{CL} = -(V_{DD} - V_{TN}^*) C_a$

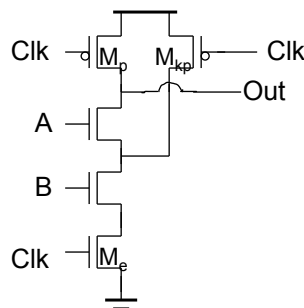
$$\rightarrow \Delta V_{Out} = -(V_{DD} - V_{TN}^*) C_a / C_L$$

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Solution to Charge Sharing



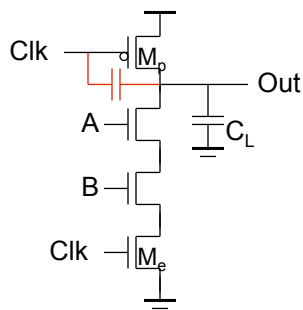
- Keeper helps a lot
 - Can still get failures if Out drops below inverter V_{sw}
- Another option: precharge internal nodes
 - Increases power and area

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Issues in Dynamic Design 3: Clock Feedthrough



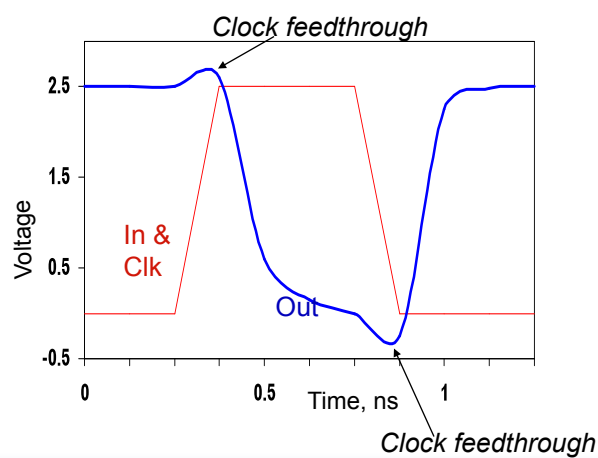
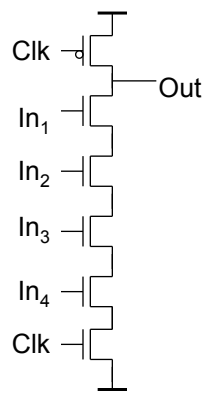
Coupling between Out and Clk input of the precharge device due to the gate to drain capacitance. So voltage of Out can rise above V_{DD} . The fast rising (and falling edges) of the clock **couple** to Out.

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Clock Feedthrough

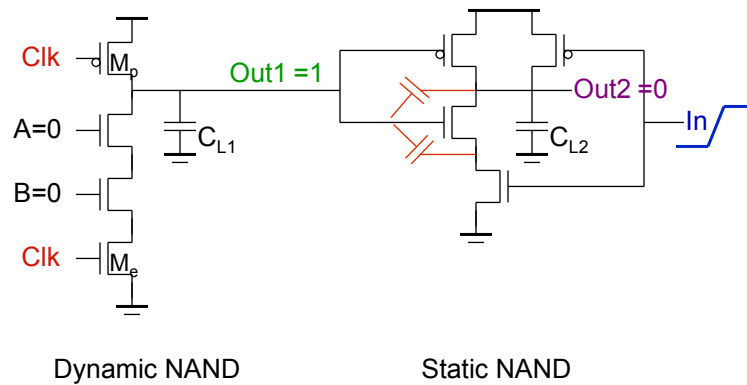


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Issues in Dynamic Design 4: Backgate Coupling

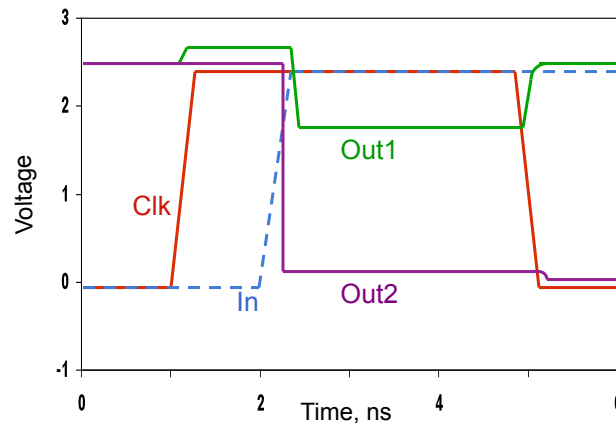


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Backgate Coupling Effect



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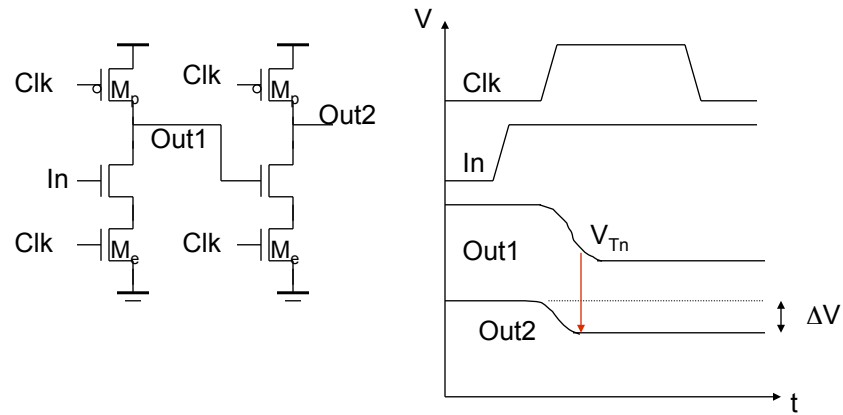
Other Effects

- ❑ Capacitive coupling
- ❑ Substrate coupling
- ❑ Minority charge injection
- ❑ Supply noise (ground bounce)



Domino Logic

Cascading Dynamic Gates



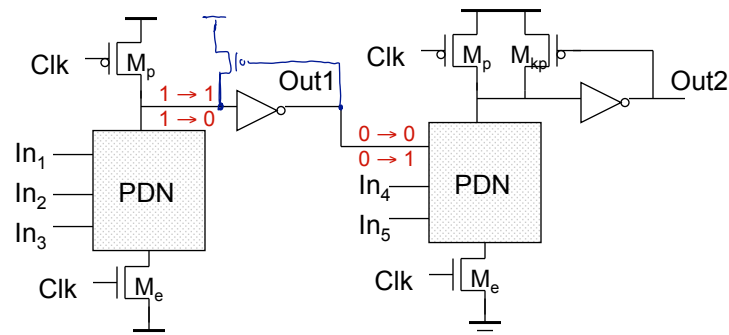
Only 0 → 1 transitions allowed at inputs!

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Domino Logic

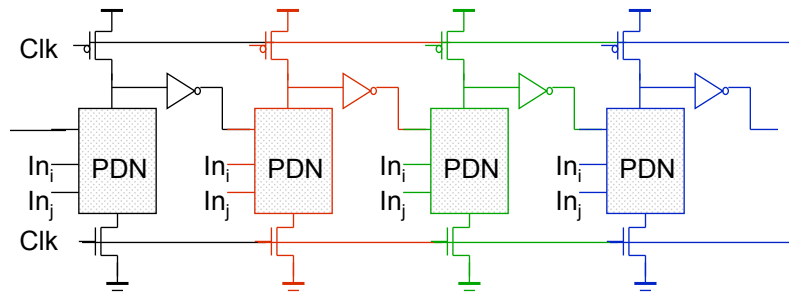


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Why Named Domino?

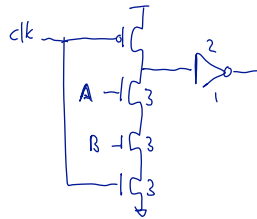


Like falling dominos!

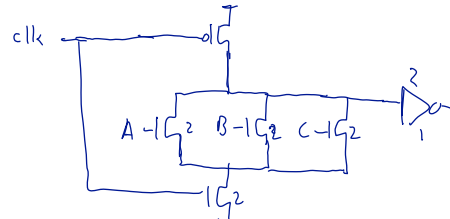
Properties of Domino Logic

- ❑ Only non-inverting logic can be implemented
- ❑ Very high speed
 - static inverter can be skewed, only L-H transition critical
 - Input capacitance reduced – smaller logical effort

Domino Logic LE



$$\begin{aligned} LE_{dyn} &= \\ LE_{inv} &= 1 \\ \pi LE &= \end{aligned}$$



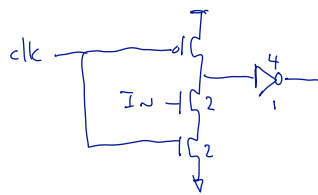
$$\begin{aligned} LE_{dyn} &= \\ LE_{inv} &= 1 \\ \pi LE &= \\ LE_{static} &= \frac{7}{3} \end{aligned}$$

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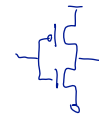
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Domino Logic LE (skewed static gate)



$$\begin{aligned} LE_{dyn} &= \\ LE_{inv} &= \\ \pi LE &= \end{aligned}$$

reference inverter:

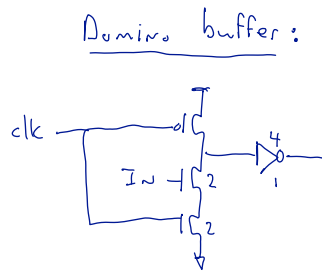


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Buffer "Average" LE



$$LE_{\text{drive}} = \frac{2}{3}$$

$$LE_{\text{sink}} = \frac{5}{6}$$

$$\pi LE = \frac{10}{18}$$

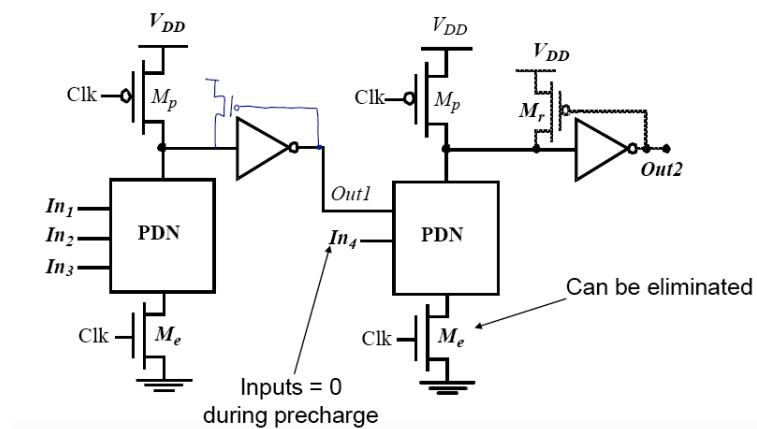
$$\text{"Average" } LE = \sqrt{10/18} \approx \frac{3}{4}$$

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Designing with Domino Logic



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